

**Notice of References Cited**

Application/Control No.

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Applicant(s)/Patent Under

Reexamination

STEFFL, UDO

Examiner

RIP A. LEE

Art Unit

1796

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,114,522	05-1992	Takado et al.	156/245
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
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	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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**NON-PATENT DOCUMENTS**

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